

<b>Notice of References Cited</b>	Application/Control No. 10/693,546		Applicant(s)/Patent Under Reexamination CHASE, JOHN R.	
	Examiner SUZANNE LO		Art Unit 2128	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,085,702	08-2006	Hwang et al.	703/15
*	B	US-2004/0210798	10-2004	Higashi, Shinsaku	714/027
*	C	US-5,805,795	09-1998	Whitten, Thomas G.	714/38
*	D	US-6,907,550	06-2005	Webster et al.	714/47
*	E	US-6,378,088	04-2002	Mongan, John Thomas	714/39
*	F	US-6,189,116	02-2001	Mongan et al.	714/38
*	G	US-6,678,645	01-2004	Rajsuman et al.	703/20
*	H	US-6,334,207	12-2001	Joly et al.	716/17
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Bening et al. "Optimizing Multiple EDA Tools within the ASIC Design Flow", 2001, IEEE, IEEE Design & Test of Computers, pages 46-55
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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